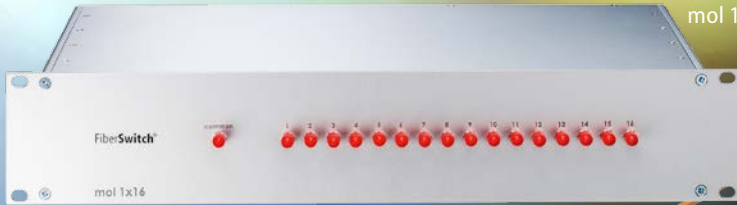


Optical switch integrated defect detection system for semiconductor manufacturing



mol 1x16 19" 2 HU



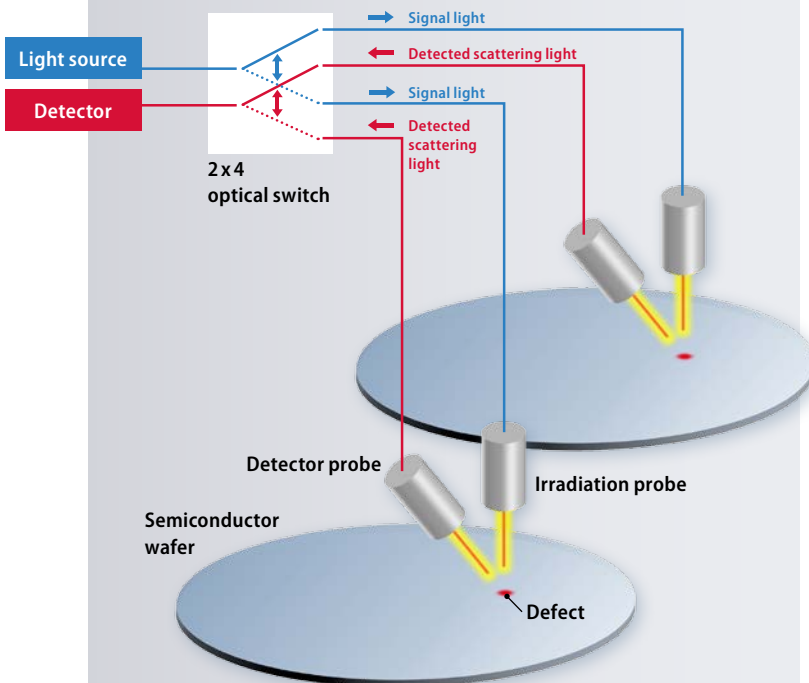
mol 2x4

FiberSwitch[®]
Light Switching for Optical Systems

Detecting defects in semiconductor wafers with integrated 2xN optical switch

In a semiconductor wafer, defects can be found by detecting scattering light. By integrating LEONI 2xN optical switches, a light source and a detector can be shared. The system can be downsized and the throughput can be enhanced. LEONI optical switches will be applicable to some enhanced configurations, such as a multiple light source system. LEONI supplies various types of single- & multimode switches, i.e. LargeCore fibers up to 800 μm , PM, UV-VIS, VIS-IR and broadband.

As an OEM service partner we can also easily integrate the switch into the final measuring system.



Specifications	
Number of channels N	1x2, 1x4, 1x8, 1x12, 1x16, 2x4, 2x8 (2 ports are switched synchronously) → Other channel counts on request
Operating wavelength [nm]	Depending only on fiber characteristic
Switching frequency [s^{-1}]	≤ 50

LEONI